

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/542,769	<b>Applicant(s)/Patent under Reexamination</b> BUTZKE ET AL.
<b>Examiner</b> Mohammad Meah	<b>Art Unit</b> 1652	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
sequence		5/26/06	STIC

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
east	6/26/2006	MYM
stn	6/26/2006	MYM
sequence	5/26/06	STIC